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## Shot Peened Surface Characterization Using 3D Metrology

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#### ABSTRACT

Shot peening is a surface modification process involving the impacting of round metal, glass or ceramic beads to impart a degree of surface roughness and/or a specified surface topography on a product surface. Three-dimensional (3D) non-contact profilometry is a significant new tool for characterizing shot-peened surfaces. This paper discusses the information that can be derived from this technique.

Keywords: shot-peening, profilometry, 3D non-contact profilometry

#### Introduction

Shot peening is a process by which a substrate is impacted with round metal, glass or ceramic beads, also known as shot, at a force intended to create plasticity on the surface. The characteristics present prior to and after the peening process provides vital information to better the understanding and control of the process. Among many others, surface roughness and dimple coverage area left by the shot, are of particular interest.

#### Importance of a 3D non-contact profilometer for peened surfaces

Unlike traditional contact profilometers which traditionally have been used to measure peened surfaces, 3D non-contact measurement provides a full 3D image to give a more complete understanding of coverage area and surface topography. Without 3D capabilities, an inspection will be solely relying on 2D information, which provides insufficient information for characterizing a surface. Understanding the topography, coverage area and roughness in 2D is heat ontion to particular the people area and roughness in 2D information.

3D is the best option to control or improve the peening process. The 3D non-contact

profilometers<sup>\*\*</sup> utilize chromatic confocal technology with unique capability to measure the steep angles found with machined and peened surfaces. Additionally, where other techniques fail to provide reliable data, due to probe contact, surface variation, angle or reflectivity,

3D profilometers succeed.

#### Measurement objective

In this application, a 3D profilometer is used to measure raw material and two differently peened surfaces for a comparative review. There is an endless list of surface parameters that can be automatically calculated after the 3D surface scan. Here we will review the 3D surface and select areas of interest to further analyze, including quantifying and investigating the roughness, dimples and surface area.

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#### **Measurement Principle**

As shown in Fig. 1, the axial chromatism technique uses a white light source, where light passes through an objective lens with a high degree of chromatic aberration. The refractive index of the objective lens will vary in relation to the wavelength of the light. In effect, each separate wavelength of the incident white light will re-focus at a different distance from the lens (different height).



Figure 1 - Schematic diagram of the measurement principle used in 3D profilometry.

When the measured sample is within the range of possible heights, a single monochromatic point will be focalized to form the image. Due to the confocal configuration of the system, only the focused wavelength will pass through the spatial filter with high efficiency, thus causing all other wavelengths to be out of focus. The spectral analysis is done using a diffraction grating. This technique deviates each wavelength at a different position, intercepting a line of CCD, which in turn indicates the position of the maximum intensity and allows direct correspondence to the Z height position.

The optical pens have zero influence from sample reflectivity. Variations require no sample preparation and have advanced ability to measure high surface angles. The pens are capable of large Z measurement ranges. Any material - transparent/opaque, specular/diffusive, polished/rough - can be measured. The measurements include profile dimension, roughness finish texture, shape form topography, flatness warpage planarity, volume area, step-height depth thickness and many others.

#### **Experimental results**

In this study, we have shown how the the 3D non-contact profilometer can precisely characterize both the topography and the nanometer details of a peened surface. As a base line, profilometry results are shown in Fig. 2 for an unpeened steel surface. Figures 3 and 4 show the results for two separate peened steel specimens, designated Surface 1 and Surface 2, respectively.

We can clearly see that both Surfaces 1 and 2 have a significant effect on all parameters reported here when compared to the raw material. The images show that Surface 1 and 2 are visually different. This is further verified by looking at the coverage area and the parameters listed. Compared to Surface 2, Surface 1 shows a lower average roughness ( $S_a$ ), dents that were not as deep ( $S_v$ ), less surface area ( $S_{dar}$ ), but a slightly higher coverage area.

From these 3D surface measurements, areas of interest can quickly be identified and analyzed with a comprehensive list of measurements (dimension, roughness finish texture, shape form topography, flatness warpage planarity, volume area, stepheight, etc.). A 2D cross-section can quickly be chosen to analyze further details. With this information, peened surfaces can be broadly investigated with a complete set of surface measurement resources.



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#### Additional advantages of 3D profilometry

**RESULTS:** 

This study shows the potential advantages to be gained with 3D profilometry. Beyond what is shown here, additional detailed characterization can be obtained with an integrated atomic force microscopy (AFM) module. With scanning speeds ranging from 20 mm/sec to 1.0 m/sec, applications can range from laboratory research to of high-speed inspection.

#### Acknowledgement

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#### 3D Measurement of Steel Surface

Sa	0.399µm	Average Roughness	
Sq	0.516µm	RMS Roughness	
Sz	5.686µm	Maximum Peak-to-Valley	
Sp	2.976µm	Maximum Peak Height	
Sv	2.711µm	Maximum Pit Depth	
Sku	3.9344	Kurtosis	
Ssk	-0.0113	Skewness	
Sal	0.0028mm	Auto-Correlation Length	
Str	0.0613	Texture Aspect Ratio	
Sdar	26.539mm <sup>2</sup>	Surface Area	
Svk	0.589µm	Reduced Valley Depth	

3D Roughness Parameters ISO 25178

Figure 2 - 3D Profilometry data for an unpeened steel surface.



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#### **3D Measurement of Shot Peen Surface 1**

#### Surface Coverage 98.105%

#### 3D Roughness Parameters ISO 25178



Sa	4.102µm	Average Roughness	
Sq	5.153µm	RMS Roughness	
Sz	44.975µm	Maximum Peak-to-Valley	
Sp	24.332µm	Maximum Peak Height	
Sv	20.644µm	Maximum Pit Depth	
Sku	3.0187	Kurtosis	
Ssk	0.0625	Skewness	
Sal	0.0976mm	Auto-Correlation Length	
Str	0.9278	Texture Aspect Ratio	
Sdar	29.451mm <sup>2</sup>	Surface Area	
Svk	5.008µm	Reduced Valley Depth	

### Figure 3 - 3D Profilometry data for peened steel surface #1.



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### **RESULTS:** Peened Surface 2





#### 3D Measurement of Shot Peen Surface 2

Surface Coverage 97.366%

3D Roughness Parameters ISO 25178



Sa	4.330µm	Average Roughness
Sq	5.455µm	RMS Roughness
Sz	54.013µm	Maximum Peak-to-Valley
Sp	25.908µm	Maximum Peak Height
Sv	28.105µm	Maximum Pit Depth
Sku	3.0642	Kurtosis
Ssk	0.1108	Skewness
Sal	0.1034mm	Auto-Correlation Length
Str	0.9733	Texture Aspect Ratio
Sdar	29.623mm <sup>2</sup>	Surface Area
Svk	5.167µm	Reduced Valley Depth

